

1. Features

- $R_{DS(ON)}=4.4m\Omega(\text{typ.})@V_{GS}=10V$
- Very Low On-resistance $R_{DS(ON)}$
- Low C_{rss}
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

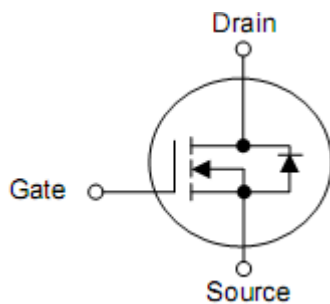
2. Applications

- PWM Application
- Power Management
- Load switch

3. Symbol



TO-252



| Pin | Function |
|-----|----------|
| 1 | Gate |
| 2 | Drain |
| 3 | Source |

4. Ordering Information

| Part Number | Package | Brand |
|-------------|---------|-------|
| KND3404D | TO-252 | KIA |

5. Absolute maximum ratings

$T_C=25^{\circ}\text{C}$ unless otherwise noted

| Parameter | Symbol | Rating | Units | |
|---|---------------------------|------------|--------------------|---|
| Drain-source voltage | V_{DSS} | 40 | V | |
| Continuous drain current | $T_C=25^{\circ}\text{C}$ | I_D | 80 | A |
| | $T_C=100^{\circ}\text{C}$ | I_D | 52 | A |
| Pulsed drain current -Pulsed ¹⁾ | I_{DM} | 320 | A | |
| Gate-source voltage | V_{GS} | ± 20 | V | |
| Single pulse avalanche energy ²⁾ | E_{AS} | 104 | mJ | |
| Power dissipation ($T_C=25^{\circ}\text{C}$) | P_D | 77 | W | |
| Operating junction and storage temperature range | T_J, T_{STG} | -55 to 150 | $^{\circ}\text{C}$ | |
| Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds | T_L | 300 | $^{\circ}\text{C}$ | |

*Drain current limited by maximum junction temperature.

6. Thermal characteristics

| Parameter | Symbol | Rating | Unit |
|----------------------------------|-----------------|--------|----------------------|
| Thermal resistance junction-case | $R_{\theta JC}$ | 1.95 | $^{\circ}\text{C/W}$ |

7. Electrical characteristics

(T_C=25°C unless otherwise noted)

| Parameter | Symbol | Test Conditions | Min | Typ | Max | Units |
|---|---------------------|--|-----|------|------|-------|
| Drain-source breakdown voltage | BV _{DSS} | V _{GS} =0V, I _D =250uA | 40 | - | - | V |
| Drain-source leakage current | I _{DSS} | V _{DS} =40V, V _{GS} =0V | - | - | 1 | uA |
| | | V _{DS} =32V, T _C =125°C | - | - | 10 | uA |
| Gate-source forward leakage | I _{GSS} | V _{GS} =±20V, V _{DS} =0V | - | - | ±100 | nA |
| Gate threshold voltage | V _{GS(TH)} | V _{DS} = V _{GS} , I _D =250uA | 1.0 | 1.5 | 2.5 | V |
| Drain-source on-resistance | R _{DS(on)} | V _{GS} =10V, I _D =30A | - | 4.4 | 5.5 | mΩ |
| | | V _{GS} =4.5V, I _D =20A | - | 6.5 | 10 | mΩ |
| Input capacitance | C _{iss} | V _{DS} =20V, V _{GS} =0V f=1MHz | - | 3045 | - | pF |
| Output capacitance | C _{oss} | | - | 388 | - | pF |
| Reverse transfer capacitance | C _{rss} | | - | 234 | - | pF |
| Turn-on delay time | t _{d(on)} | V _{GS} =10V, V _{DS} =20V, R _G =3Ω, I _D =30A | - | 6 | - | ns |
| Rise time | t _r | | - | 17 | - | ns |
| Turn-off delay time | t _{d(off)} | | - | 23 | - | ns |
| Fall time | t _f | | - | 12 | - | ns |
| Total gate charge(10V) | Q _g | V _{DS} =20V, I _D =30A V _{GS} =10V | - | 58 | - | nC |
| Gate-source charge | Q _{gs} | | - | 10 | - | nC |
| Gate-drain charge | Q _{gd} | | - | 9 | - | nC |
| Maximum Continuous Drain-Source Diode Forward Current | I _S | — | - | - | 80 | A |
| Maximum Pulsed Drain-Source Diode Forward Current | I _{SM} | — | - | - | 320 | A |
| Diode forward voltage | V _{SD} | I _{SD} =30A, V _{GS} =0V, T _J =25°C | - | - | 1.2 | V |
| Reverse Recovery Time | t _{rr} | I _F =20A, di/dt=100A/μs T _J =25°C | - | 22 | - | nS |
| Reverse Recovery Charge | Q _{rr} | | - | 11 | - | nC |

Note:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
2. EAS condition: T_J=25°C, V_{DD}=20V, V_G=10V, L=0.5mH, R_G=25Ω, I_{AS}=20A
3. Pulse Test: Pulse Width≤300μs, Duty Cycle≤0.5%

8. Typical operating characteristics

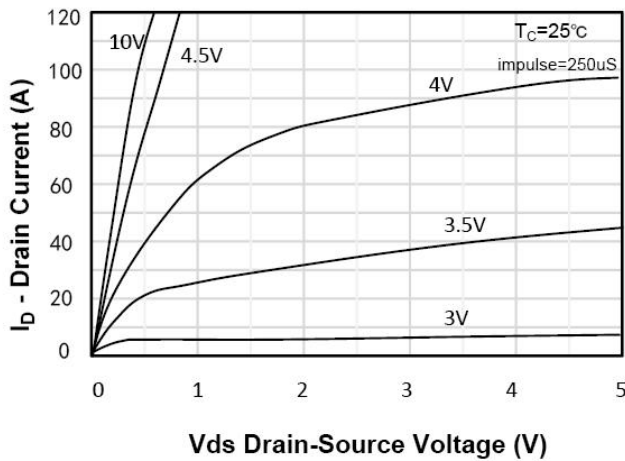


Figure 1. On-Region Characteristics

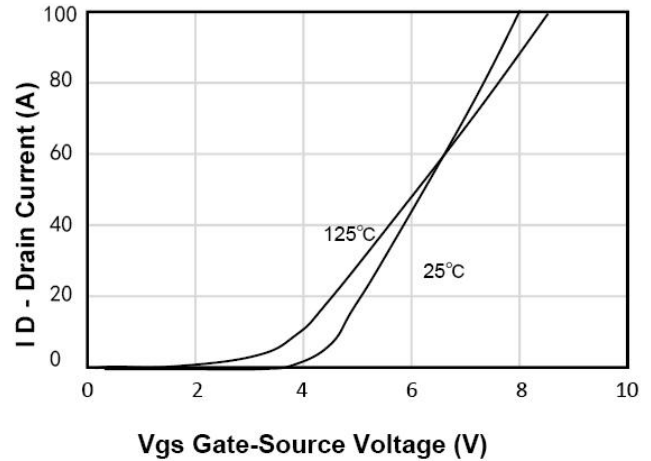


Figure 2. Transfer Characteristics

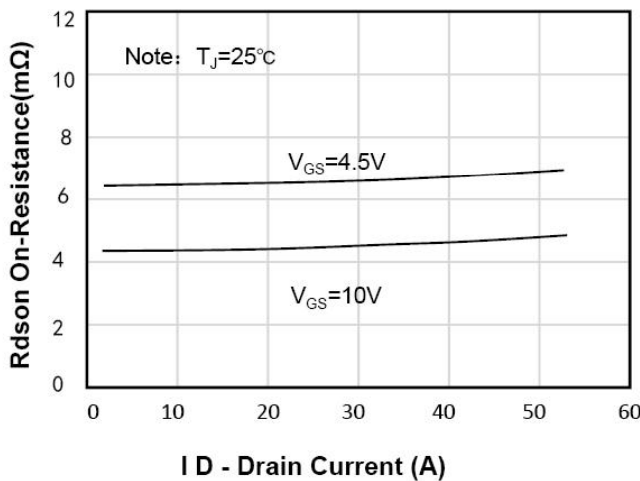


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

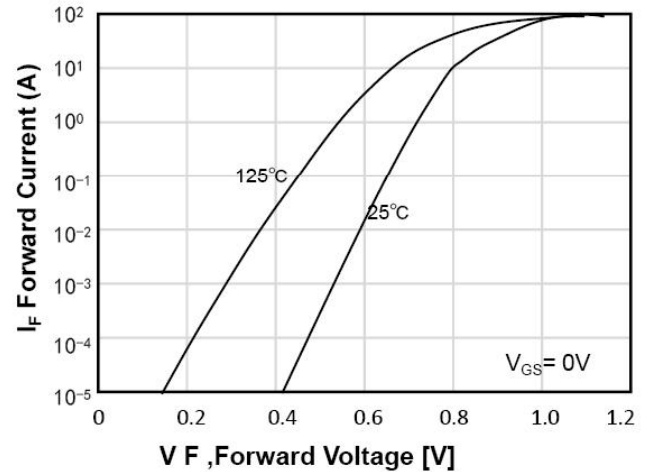


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

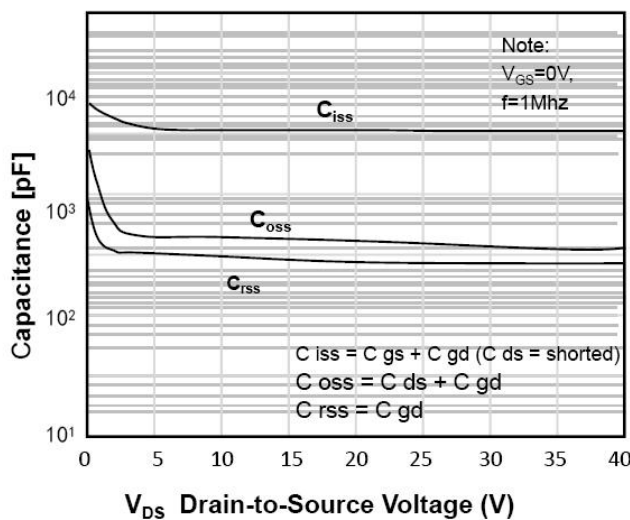


Figure 5. Capacitance Characteristics

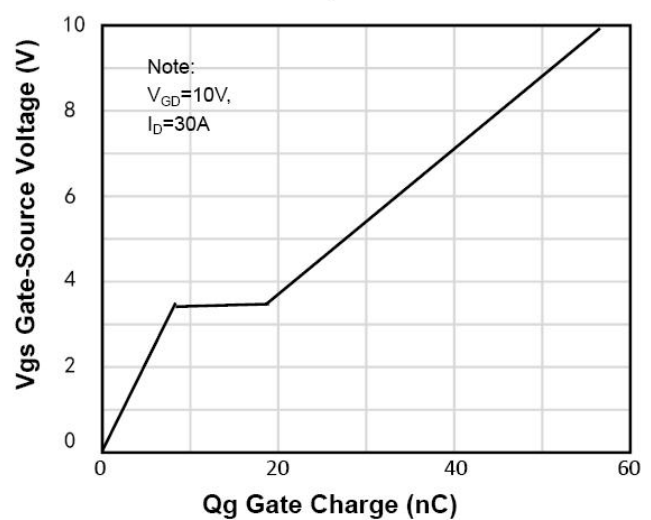


Figure 6. Gate Charge Characteristics

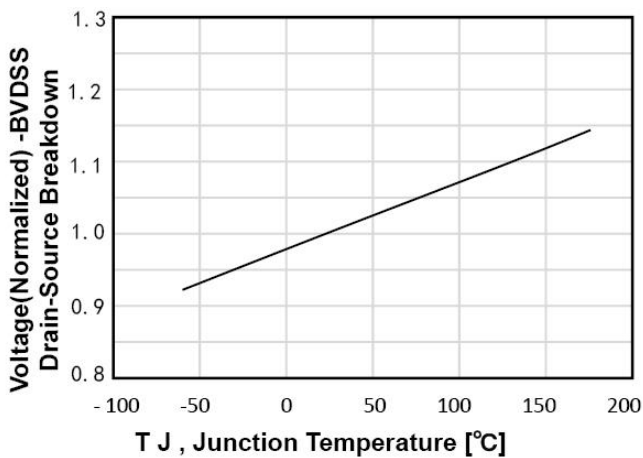


Figure 7. Breakdown Voltage Variation vs Temperature

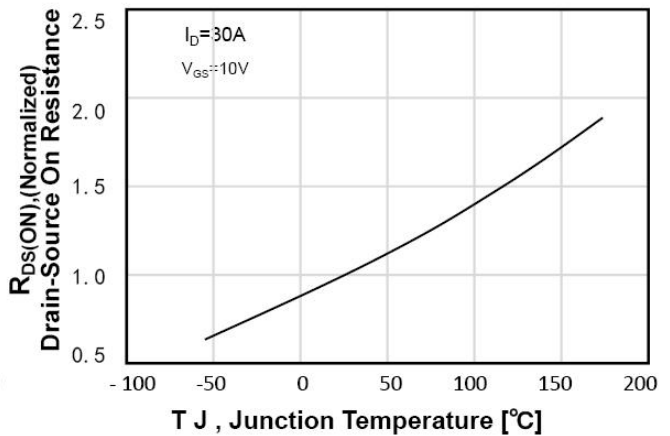


Figure 8. On-Resistance Variation vs Temperature

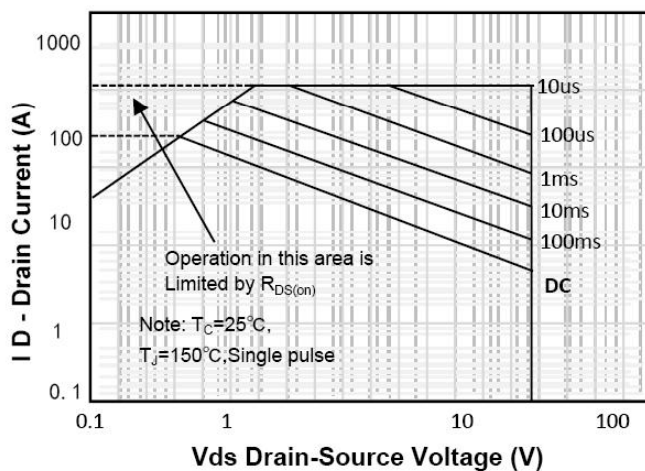


Figure 9. Maximum Safe Operating Area

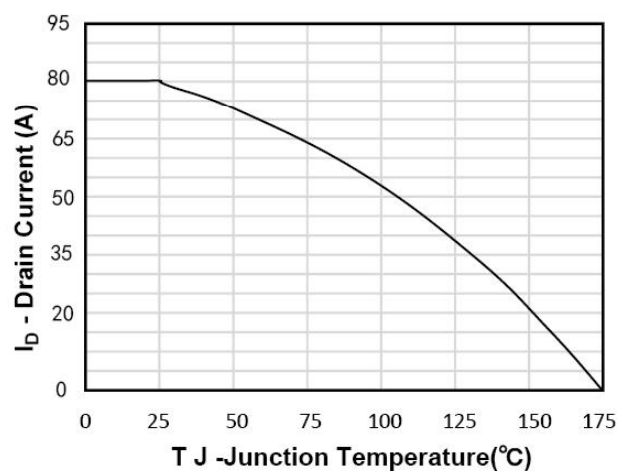


Figure 10. V ds Drain VS Junction Temperature

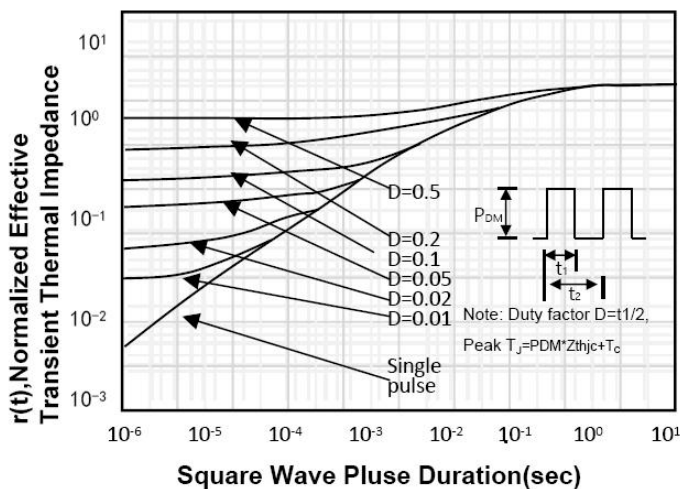
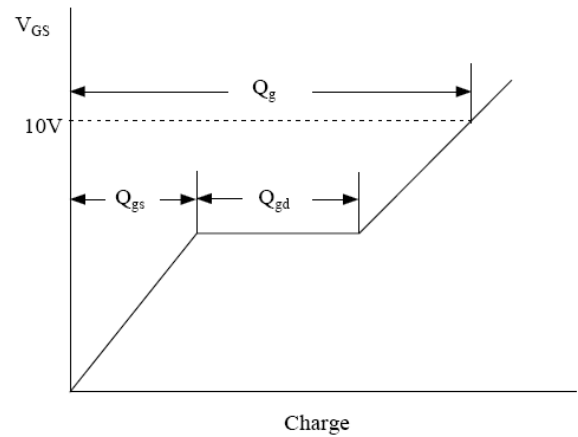
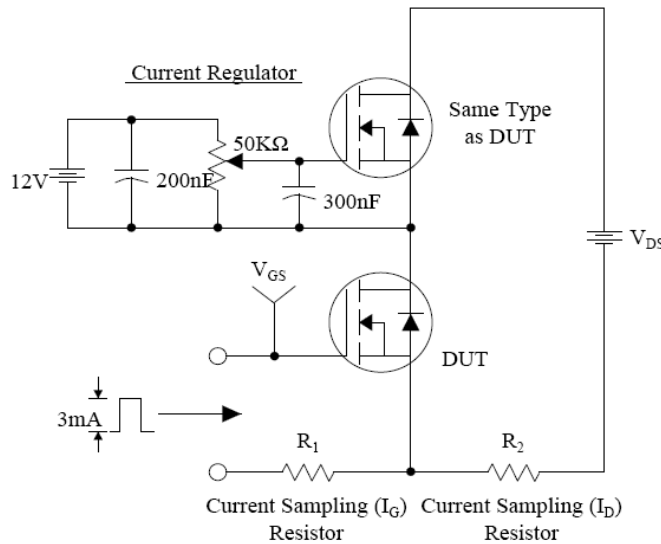


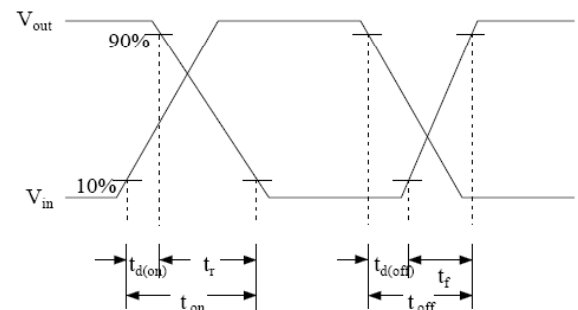
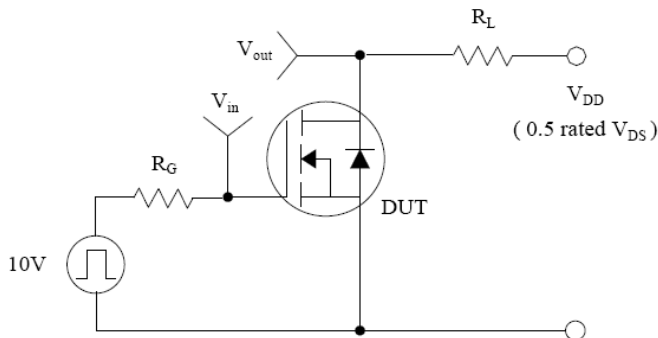
Figure 11. Transient Thermal Response Curve

9. Test Circuits and Waveforms

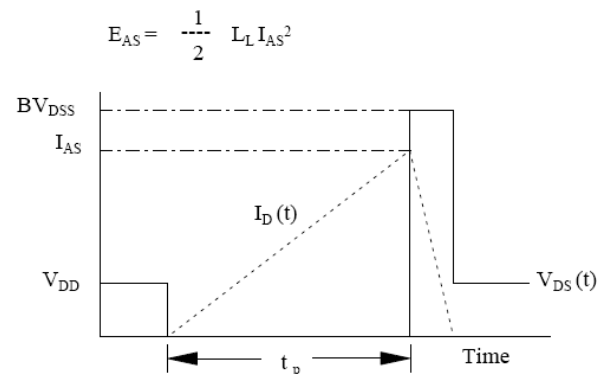
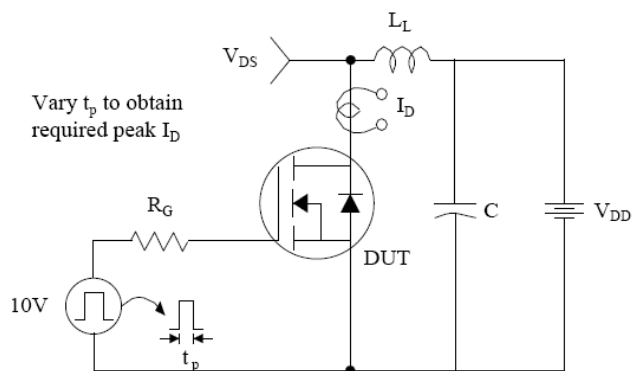
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms

